

13th RD50 Workshop

Monday, 10 November 2008

Defect and Material Characterization - 40-S2-D01 (13:45 - 16:20)

time	[id] title	presenter
13:45	[9] Radiation induced point- and cluster-related defects with strong impact to damage properties of silicon detectors	FRETWURST, Eckhart
14:15	[3] Anneal dependent variations of lifetime and deep levels in neutron irradiated MCZ Si	Prof. VAITKUS, Juozas
14:35	[6] Recent results on bistable cluster related defects	JUNKES, Alexandra
14:55	[18] Characterisation of defect centres in epitaxial silicon irradiated with high proton fluences	KAMINSKI, Pawel
15:15	Coffee break	
15:45	[14] Discussion Session: Defect and Material Characterization	